

DPCI (Derwent Patents Citation Index[™])

Subject Coverage	All areas of science and technology, i.e., all classes of the International Patent Classification	
File Type	Bibliographic	
Features	<p>Thesaurus There is a thesaurus-like feature in the Patent Assignee Code (/PACO)</p> <p>Alerts (SDIs) Weekly or monthly (Every update is the default)</p> <p>CAS Registry <input type="checkbox"/> Page Images <input type="checkbox"/> STN[®] AnaVist[™] <input type="checkbox"/></p> <p>Number[®] Identifiers</p> <p>Keep & Share <input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/> STN Easy@ <input checked="" type="checkbox"/></p> <p>Learning Database <input checked="" type="checkbox"/> Structures <input type="checkbox"/></p>	
Record Content	Bibliographic patent family data from Derwent World Patents Index [®] and all patents and literature cited by examiners, as well as references to citing patents.	
File Size	<ul style="list-style-type: none"> • More than 19 million records (2/17) • More than 98 million patent citations (2/17) • More than 11 million literature citations (2/17) 	
Coverage	1973-present	
Updates	Weekly	
Language	English	
Database Producer	<p>Clarivate Analytics (UK) Limited Friars House, 160 Blackfriars Rd. London SE1 8EZ United Kingdom</p> <p>Copyright Holder: Clarivate Analytics</p>	
Sources	DPCI provides patent citation information from 32 sources as detailed below:	
	Country	Start Date
	Australia (AU)	January 1993
	Belgium (BE)	January 1988
	China (CN)	January 2010
	Czech Republic (CZ)	June 2006
	European (EP)	December 1978
	France (FR)	January 1974
	Germany (DE)	January 1974
	Japan (JP)	January 1994
	Korea (KR)	January 2008
	Luxembourg (LU)	July 1999

Sources	Country	Start Date
	Malaysia (MY)	January 2010
	Netherlands (NL)	January 1974
	PCT (WO)	October 1978
	Philippines (PH)	November 2009
	Russia (RU)	June 2009
	Singapore (SG)	March 2001
	South Africa	1994
	Spain (ES)	January 1993
	Switzerland (CH)	January 1986
	United Kingdom (GB)	January 1979
	United States (US)	January 1970

Limited coverage is included for the following:

Country	Start Date
Austria (AT)	1994-1996
Brazil (BR)	
Canada (CA)	1994-1996
Denmark (DK)	
Finland (FI)	
German Democratic Republic (DD)	
Ireland (IE)	
Italy (IT)	
New Zealand (NZ)	1994-1996
Norway (NO)	
Sweden (SE)	1994-1996

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- User Aids**
- DPCI Reference Manual: <http://www.stn-international.de/dpciman.html>
 - Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE

-
- Clusters**
- ALLBIB
 - HPATENTS
 - PATENTS
- [STN Database Clusters](#) information (PDF)

Pricing

Enter HELP COST at an arrow prompt.

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

Master Patent Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from the title (TI) only)	None or /BI	S DRILLING FLUID AND EMULS? S PHENYLETHER? S ULCER TREATMENT	TI
Accession Number Application Country (WIPO code and text) (1) Application Date (1,2) Application Number (1,3)	/AN /AC /AD /AP	S 1993-126101/AN S AU/AC S AUSTRALIA/AC S FR/PC (P) JUNE 1986/AD S 1989GB-0219641/AP S GB1989-219641/AP S 1949GB-000017120/APTS	AN ADT ADT ADT
Application Number, Clarivate Analytics. Format Application Type Application Year (2) Country Count (2) DERWENT Week (2,4)	/APTS /APT /AY /CYC /DW	 S RELATED TO/APT S 1990-1991/AY S 20-30/CYC S 199108/DW S 199301-9315/DW(P)FR/PC S 199315/DW.B(P)US/PC.B S BE/DS S RW: BE/DS(P)1990/PY	 ADT CYC PI
DERWENT Week Basic (2,4) Designated State (4)	/DW.B /DS	S 199315/DW.B(P)US/PC.B S BE/DS S RW: BE/DS(P)1990/PY	PI PI
Document Type Entry Date (2) Field Availability Filing Details (3,4)	/DT /ED /FA /FDT	S L7 AND P/DT S ED>JAN 2011 S FDT/FA S US5072794/FDT S EP-105613/FDT	not displayed ED FA FDT
Filing Details, Patent Country (WIPO code and text) Filing Details, Patent Kind Code Filing Details, Patent Publication Number (3) Filing Details, Type Inventor	/FDT.PC /FDT.PK /FDT.PN /FDT.TP /IN (or /AU) /LA	S AUSTRIA/FDT.PC S AT/FDT.PC S ATA/FDT.PK S AT2000000032/FDT.PN S BASED ON/FDT.TP S HALE, A H/IN S HALE A H/IN,PA S FR/LA(P)EP/PC S FRENCH/LA(P)EP/PC(P)1990/PY	FDT FDT FDT FDT IN
Language (code and text) (4) Number of Drawings Number of Pages Patent Assignee (5)	/DRWN /PGN /PA (or /CS)	S 9-10/DRWN S 10-15/PGN S SHELL OIL/PA S "NEW YORK WIRE"?/PA	PI PI PA
Patent Assignee Code Patent Countries (WIPO code and text) (contains PC, DS) (4) Patent Country (WIPO code and text) (4) Patent Country Basic (WIPO code and text) (4) Patent Kind Code (4)	/PACO /PCS /PC /PC.B /PK	S SHEL/PACO S ES/PCS S SPAIN/PCS S GB/PC(P)1989/AY S UNITED KINGDOM/PC S GB/PC.B(P)JUNE 92/PD.B S GBA/PK S EPA2/PK(P)DE/DS S EPA/PK.B S EPA1/PK.B(P)1991-1992/PY.B	PA PI PI PI PI PI
Patent Kind Code Basic (4)	/PK.B	S EPA1/PK.B(P)1991-1992/PY.B	PI

Search and Display Field Codes

Master Patent Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Patent Number (3,4)	/PN	S US5198416/PN S EP-100323/PN S EP0100323/PN S EP100323/PN	PI
Patent Number Basic (3,4)	/PN.B	S US5198416/PN.B	PI
Patent Number Count (2)	/PNC	S 5-10/PNC	PNC
PCI Update	/DUPD	S 200709/DUPD	DUPD
PCI Week	/PCIW	S 201063/PCIW	PI
Priority Country (6)	/PRC	S FR/PRC S GB/PRC(S)1990/PRY	PRAI
Priority Date (2,6)	/PRD	S 19880930/PRD S JUNE 1991/PRD(S)FR/PRC	PRAI
Priority Date First (2,6)	/PRDF	S JUNE 1991/PRDF	PRAI
Priority Number (3,6)	/PRN	S 88US-0252206/PRN S US88-252206/PRN S DE1991-10049/PRN S 1991DE-10049/PRN	PRAI
Priority Number, Clarivate Analytics	/PRTS	S 2007WO-JP0057178/PRTS	PRTS
Priority Year (2,6)	/PRY	S 1990-1991/PRY(S)NL/PRC	PRAI
Priority Year First (2,6)	/PRYF	S 1992/PRYF	PRAI
Publication Date (2,4)	/PD	S 19900404/PD S 1 APR 1990-15 APR 1990/PD(P)GB/PC	PI
Publication Date Basic (2,4)	/PD.B	S 19930330/PD.B(P)US/PC.B	PI
Publication Year (2,4)	/PY	S 1990-1991/PY	PI
Publication Year Basic (2,4)	/PY.B	S 1990/PY.B(P)JP/PC.B	PI
Title *	/TI	S DRILLING FLUID#/TI	TI
Update Date (PCI) (2)	/UP	S L7 AND UP=20071212	UP
Update Date Citations	/UPD	S 20110102/UPD	UPD
Update Date Citings	/UPG	S 20110102/UPG	UPG

- (1) Application information is linked by (P) proximity to the patent information (PN, PK, PC) of the respective document. Search with (S) proximity when referring to application data of the same application.
- (2) Numeric search field that may be searched using numeric operators or ranges.
- (3) Numbers are searchable in Derwent and STN format.
- (4) Patent information and application information of one patent document is linked by (P) proximity.
- (5) Search with implied (S) proximity is available in this field.
- (6) Priority information referring to the same application is linked by (S) proximity.

Super Search Fields (1)

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (2) Patent Number Group (2)	/APPS /PATS	/AP, /PRN /PN, /FDT.PN	S DE1996-19601116/APPS S EP100323/PATS	ADT, PRAI PI, FDT

(1) Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

(2) Numbers are searchable in Derwent and STN format.

Citation Fields from PCI Examiner Field of Search

Search Code	Definition	Search Examples	Display Codes
/IC.F (/RPIC)	International Patent Classification of examiner's field of search	S A61M023-00/IC.F	CITNB, EXFB
/NCL.F (/RPCL)	National Classification of examiner's field of search	S 000032000/NCL.F	CITN, EXF

Citation Fields – Master Family

Search Code	Definition	Search Examples	Display Codes
/PC.F	Patent Country of Family Member	S BE/PC.F	CITN, CGP
/PK.F	Cited Patent Kind Code of Family Member	S BELGIUM/PC.F	CITN, CGP
/PN.F (1)	Patent Number of Family Member	S AUA/PK.F S AT395571/PN.F	CITN, CGP

(1) Numbers are searchable in Derwent and STN format.

Citation Fields - Cited Patents

Search Field Name	Search Code	Search Examples	Display Codes
Cited Patent Assignee (2,3)	/PA.D	S HEIDELBERGER DRUCKMASCH?/PA.D	CDP
Cited Patent Assignee (by examiner) (2,3)	/PA.DX	S ANHEUSER BUSCH/PA.DX S SANYO/PA.DX(P)Y/CAT.D	CDP
Cited Patent Assignee (by inventor) (2,3,5)	/PA.DI	S SANYO ELEC?/PA.DI	CDP
Cited Patent Assignee (by third party)	/PA.DTH	S BASF CORP/PA.DTH	CDP
Cited Patent Assignee (in opposition)	/PA.DO	S BASF AG/PA.DO	CDP
Cited Patent Assignee Code (2)	/PACO.D	S BADI/PACO.D	CDP
Cited Patent Assignee Code (by inventor) (2,5)	/PACO.DI	S SONY/PACO.DI	CDP
Cited Patent Assignee Code (by third party)	/PACO.DTH	S HENK/PACO.DTH	CDP
Cited Patent Assignee Code (in opposition)	/PACO.DO	S SUMO/PACO.DO	CDP
Cited Patent Assignee Code (by examiner) (2)	/PACO.DX	S DIGI/PACO.DX	CDP
Cited Patent Category (2)	/CAT.D	S P/CAT.D	CDP
Cited Patent Country (WPIO code and text) (2)	/PC.D	S FR/PC.D S FRANCE/PC.D	CDP
Cited Patent Country (by examiner) (2) (WIPO code and text)	/PC.DX	S PL/PC.DX(P)US/PC.F S POLAND/PC.DX	CDP
Cited Patent Country (by inventor) (WIPO code and text) (2,5)	/PC.DI	S US/PC.DI S UNITED STATES/PC.DI	CDP
Cited Patent Country (by third party)	/PC.DTH	S AR/PC.DTH	CDP
Cited Patent Country (in opposition)	/PC.DO	S AT/PC.DO	CDP
Cited Patent Inventor (2)	/IN.D	S BENDER M/IN.D	CDP
Cited Patent Inventor (by examiner) (2)	/IN.DX	S ANDERSON A F/IN.DX	CDP
Cited Patent Inventor (by inventor) (2,5)	/IN.DI	S SMID, A/IN.DI	CDP
Cited Patent Inventor (by third party)	/IN.DTH	S KUNZ W/IN.DTH	CDP
Cited Patent Inventor (in opposition))	/IN.DO	S KUNZ M/IN.DO	CDP
Cited Patent Kind Code (2)	/PK.D	S DEC/PK.D	CDP
Cited Patent Kind Code (by inventor) (2,5)	/PK.DI	S SEB/PK.DI	CDP
Cited Patent Kind Code (by examiner) (2)	/PK.DX	S EPB/PK.DX	CDP
Cited Patent Kind Code (by third party)	/PK.DTH	S I/PK.DTH S NLA/PK.DTH	CDP
Cited Patent Kind Code (in opposition)	/PK.DO	S I/PK.DO S KRA/PK.DO	CDP
Cited Patent Number (2,4)	/PN.D (or /RPN)	S DE2960217/PN.D S EP---4702/PN.D	CDP
Cited Patent Number (by inventor) (2,4,5)	/PN.DI	S EP476489/PN.DI	CDP
Cited Patent Number (by examiner) (2,4)	/PN.DX	S PL40533/PN.DX	CDP

Citation Fields - Cited Patents (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Cited Patent Number (by third party)	/PN.DTH	S NL1026437/PN.DTH	CDP
Cited Patent Number (in opposition)	/PN.DO	S US1160819/PN.DO	CDP
Cited Patent Publication Date	/PD.D	S PD.D=>20100400	CDP
Cited Patent Publication Year	/PY.D	S 2010/PY.D	CDP
Cited Patent WPI Accession Number (2)	/OS.D	S 91-376711/OS.D	CDP
Cited Patent WPI Accession Number (by examiner) (2)	/OS.DX	S 91-376711/OS.DX	CDP
Cited Patent WPI Accession Number (by inventor) (2)	/OS.DI	S 93-413679/OS.DI	CDP
Cited Patent WPI Accession Number (by third party)	/OS.DTH	S 2009-K39977/OS.DTH	CDP
Cited Patent WPI Accession Number (in opposition)	/OS.DO	S 2009-K39705/OS.DO	CDP
Cited Patent WPI Accession Number Count	/OSC.D	S OSC.D>15	CTCS, CTS
Cited Patent WPI Accession Number Count (by examiner)	/OSC.DX	S 18-20/OSC.DX	CDP
Cited Patent WPI Accession Number Count (by inventor)	/OSC.DI	S 20-22/OSC.DI	CDP
Cited Patent WPI Accession Number Count (by third party)	/OSC.DTH	S 6/OSC.DTH	CTCS
Cited Patent WPI Accession Number Count (in opposition)	/OSC.DO	S 5/OSC.DO	CTCS
Cited Patent WPI Accession Number Count (undefined)	/OSC.DUN	S 7/OSC.DUN	CTCS
Cited Patents Count (1)	/PNC.D (or /CDPC)	S 20-25/PNC.D	CTCS, CTS
Cited Patents Count (by examiner) (1)	/PNC.DX	S PNC.DX>50	CTCS
Cited Patents Count (by inventor) (1,5)	/PNC.DI	S 20/PNC.DI	CTCS
Cited Patents Count (by third party)	/PNC.DTH	S 5/PNC.DTH	CTCS
Cited Patents Count (in opposition)	/PNC.DO	S 3/PNC.DO	CTCS
Cited Patents Count (undefined)	/PNC.DUN	S 6/PNC.DUN	CTCS
Issuing Authority Count Cited Patents (1)	/IAC.D	S IAC.D>9 S 12-15/IAC.D	CTCS, CTS
Issuing Authority Count Cited Patents (by examiner) (1)	/IAC.DX	S 8-10/IAC.DX	CTCS
Issuing Authority Count Cited Patents (by inventor) (1,5)	/IAC.DI	S 5/IAC.DI	CTCS
Issuing Authority Count Cited Patents (by third party)	/IAC.DTH	S 7/IAC.DTH	CTCS
Issuing Authority Count Cited Patents (in opposition)	/IAC.DO	S 6/IAC.DO	CTCS
Issuing Authority Count Cited Patents (undefined)	/IAC.DUN	S IAC.DUN>20	CTCS

Citation Fields — Cited Literature

Search Field Name	Search Code	Search Examples	Display Codes
Cited Reference Count (2)	/CRC	S 9-10/CRC	CTCS, CTS
Cited Reference Count (by examiner) (2)	/CRC.X	S 10-15/CRC.X	CTCS, CTS
Cited Reference Count (by inventor) (2,5)	/CRC.I	S CRC.I>10	CTCS, CTS
Cited Reference Count (by third party)	/CRC.TH	S CRC.TH>3	CTCS
Cited Reference Count (in opposition)	/CRC.O	S 7/CRC.O	CTCS
Cited Reference Count (undefined)	/CRC.UN	S CRC.UN=20	CTCS
Patent Country of Citing Family Member (WIPO code and text)	/REPC	S BE/REPC S BELGIUM/REPC	REN
Patent Kind Code of Citing Family Member	/REPK	S USA/REPK	REN
Patent Number of Citing Family Member (4)	/REPN	S US28990/REPN S US—28990/REPN	REN
Reference (Literature)	/REN	S CLINICAL ORTHOPAEDICS/REN	REN
Reference (Literature) cited by inventor (5)	/REN.I	S (CCITT(S)DATA COMMUNICATIONS)/REN.I	REN
Reference (Literature) cited by third party	/REN.TH	S BACTERIAL/REN.TH	REN
Reference (Literature) cited in opposition	/REN.O	S KUNZ/REN.O	REN
Reference (Literature) cited by examiner	/REN.X	S CHEMICAL ABSTRACTS?/REN.X	REN
Reference Category	/RENC	S X/RENC	REN

(1) Numeric search field that may be searched with numeric operators or ranges.

(2) Data that belongs to one citation entry is linked by (P)-proximity.

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(4) Numbers are searchable in Derwent and STN format.

(5) Data available until May 1997 only.

Citation Fields – Citing Patents

Search Field Name	Search Code	Search Examples	Display Codes
Citing Patent Assignee (2,3)	/PA.G	S BRUKER MESS?/PA.G	CGP
Citing Patent Assignee (by examiner) (2,3)	/PA.GX	S AUGUSTINE MEDICAL/PA.GX S DURACELL/PA.GX(P)JP/PC.F	CGP
Citing Patent Assignee (by inventor) (2,3,5)	/PA.GI	S DURACELL/PA.GI	CGP
Citing Patent Assignee (by third party)	/PA.GTH	S "SIEMENS AG"/PA.GTH	CGP
Citing Patent Assignee (in opposition)	/PA.GO	S "BULTHAUP GMBH & CO KG"/PA.GO	CGP
Citing Patent Assignee Code (2)	/PACO.G	S BOSC/PACO.G	CGP
Citing Patent Assignee Code (by examiner) (2)	/PACO.GX	S SATN/PACO.GX	CGP
Citing Patent Assignee Code (by inventor) (2,5)	/PACO.GI	S GENE/PACO.GI	CGP
Citing Patent Assignee Code (by third party)	/PACO.GTH	S FARB-C/PACO.GTH	CGP

Citation Fields – Citing Patents (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Citing Patent Assignee Code (in opposition)	/PACO.GO	S DEGS/PACO.GO	CGP
Citing Patent Category (2)	/CAT.G	S D/CAT.G	CGP
Citing Patent Country (2)	/PC.G	S NL/PC.G S NETHERLANDS/PC.G	CGP
Citing Patent Country (by inventor)	/PC.GI	S AU/PC.GI S AUSTRALIA/PC.GI	CGP
Citing Patent Country (by third party)	/PC.GTH	S EP/PC.GTH	CGP
Citing Patent Country (in opposition)	/PC.GO	S EUROPEAN PATENT OFFICE/PC.GO	CGP
Citing Patent Country (by examiner) (2)	/PC.GX	S GB/PC.GX S UNITED KINGDOM/PC.GX	CGP
Citing Patent Inventor (by examiner) (2)	/IN.GX	S REES M/IN.GX	CGP
Citing Patent Inventor (2)	/IN.G	S JEROME M D/IN.G	CGP
Citing Patent Inventor (by inventor) (2,5)	/IN.GI	S HARVEY, J M/IN.GI	CGP
Citing Patent Inventor (by third party)	/IN.GTH	S EHRLICH R P /IN.GTH	CGP
Citing Patent Inventor (in opposition)	/IN.GO	S EHRNSPERGER B J /IN.GO	CGP
Citing Patent Kind Code (2)	/PK.G	S WOA/PK.G	CGP
Citing Patent Kind Code (by inventor) (2,5)	/PK.GI	S WOA/PK.GI	CGP
Citing Patent Kind Code (by third party)	/PK.GTH	S EPA8/PK.GTH	CDP
Citing Patent Kind Code (in opposition)	/PK.GO	S EPA1/PK.GO	CGP
Citing Patent Kind Code (by examiner) (2)	/PK.GX	S WOA/PK.GX	CGP
Citing Patent Number (2,4)	/PN.G	S CA2078966/PN.G	CGP
Citing Patent Number (by inventor) (2,4,5)	/PN.GI	S CA2078966/PN.GI	CGP
Citing Patent Number (by third party)	/PN.GTH	S EP1000863/PN.GTH	CGP
Citing Patent Number (in opposition)	/PN.GO	S EP1000121/PN.GO	CGP
Citing Patent Publication Date	/PD.G	S PD.G=20100618	CGP
Citing Patent Publication Year	/PY.G	S PY.G=2000	CGP
Citing Patent WPI Accession Number (2)	/OS.G	S 92-321151/OS.G	CGP
Citing Patent WPI Accession Number (by examiner) (2)	/OS.GX	S 92-200339/OS.GX	CGP
Citing Patent WPI Accession Number (by inventor) (2,5)	/OS.GI	S 1991-324342/OS.GI	CGP
Citing Patent WPI Accession Number (by third party)	/OS.GTH	S 2009A14148/OS.GTH	CGP
Citing Patent WPI Accession Number (in opposition)	/OS.GO	S 2007-509246/OS.GO	CGP
Citing Patent WPI Accession Number Count (1)	/OSC.G	S 13-14/OSC.G	CGP
Citing Patent WPI Accession Number Count (by examiner)	/OSC.GX	S OSC.GX>14	CGP
Citing Patent WPI Accession Number Count (by third party)	/OSC.GTH	S OSC.GTH=2	CGP
Citing Patent WPI Accession Number Count (in opposition)	/OSC.GO	S OSC.GO>5	CGP

Citation Fields – Citing Patents (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Citing Patent WPI Accession Number Count (undefined)	/OSC.GUN	S 20/OSC.GUN	GP
Citing Patents Count (1)	/CGPC	S L1 AND CGPC>2	CTCS
Citing Patents Number Count (1)	/PNC.G	S PNC.G>49	CTCS, CTS
Citing Patents Number Count (by examiner) (1)	/PNC.GX	S 30-50/PNC.GX	CTCS
Citing Patents Number Count (by inventor) (1,5)	/PNC.GI	S 9-11/PNC.GI	CTCS
Citing Patents Number Count (by third party)	/PNC.GTH	S 6/PNC.GTH	CTCS
Citing Patents Number Count (in opposition)	/PNC.GO	S 7/PNC.GO	CTCS
Citing Patents Number Count (undefined)	/PNC.GUN	S 3<PNC.GUN<5	CTCS
Issuing Authority Count Citing Patents (1)	/IAC.G	S 5/IAC.G	CTCS
Issuing Authority Count Citing Patents (by examiner) (1)	/IAC.GX	S 5-10/IAC.GX	CTCS
Issuing Authority Count Citing Patents (by inventor) (1,5)	/IAC.GI	S IAC.GI>5	CTCS
Issuing Authority Count Citing Patents (by third party)	/IAC.GTH	S I/IAC.GTH	CTCS
Issuing Authority Count Citing Patents (in opposition)	/IAC.GO	S IAC.GO>0	CTCS
Issuing Authority Count Citing Patents (undefined)	/IAC.GUN	S 3<IAC.GUN<5	CTCS
Patent Country of Family Member (WPIO code and text) (2)	/PC.F	S EP/PC.F S EP/PC.F(P)JP/PC.G	CGP, CDP
PCI Week, Citing Patents	/PCIW.G	S PCIW.G>201001	

(1) Numeric search field that may be searched with numeric operators or ranges.

(2) Data that belongs to one citation entry is linked by (P)-proximity.

(3) Search with implied (S) proximity is available in this field.

(4) Numbers are searchable in Derwent and STN format.

(5) Data available until May 1997 only.

Patent Assignee Code Dictionary

The list of Clarivate Analytics-assigned company codes for patent assignees matched with company names is available in field /PACO. This feature allows you to easily and comprehensively identify the company names associated with a code, or to identify the code(s) used for a company name. Expanding in field /PACO (Patent Assignee Code) provides the alphabetical list of codes, single words and the full name from the company field (/PA). Each code is listed with its frequency in field /PACO and with the number of associated terms (AT) in the dictionary.

Field	Relationship Code	Content	Search Examples
/PACO	ALL	All patent assignee code(s) defined for the name (SELF, DEF, CODE)	E BAYER+ALL/PACO
/PACO.D	CODE	Related codes (CODE, SELF)	E PFIZER+CODE/PACO
/PACO.DI	DEF	All name definition for the given code(SELF, DEF)	E FARB+DEF/PACO
/PACO.DO			
/PACO.DTH			
/PACO.DX			
/PACO.G			
/PACO.GI			
/PACO.GO			
/PACO.GTH			
/PACO.GX			

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PI. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Master Patent Fields

Format	Content	Examples
ADT (1)	Application Details	D ADT
ADT.B (1)	Application Details, Basic	D ADT.B
AI (AP) (1)	Application Information	D AI 1-5
AI.B (1)	Application Information, Basic	D AI.B
AN	Accession Number	D AN
CYC	Country Count	D CYC
DS	Designated States	D DS
DUPD	PCI Update Date	D DUP
ED	Entry Date (PCI)	D ED
FA	Field Availability	D FA
FDT (1)	Filing Details	D FDT
IN (AU)	Inventor	D IN
PA (CS)	Patent Assignee	D 1-10 TI PA
PI (PN) (1)	Patent Information	D PI
PI.B (PN.B) (1)	Patent Information, Basic	D PI.B
PNC	Patent Number Count	D PNC
PRAI (PRN) (1)	Priority Information	D PRAI
TI	Title	D TI
UP	Update Date	D UP

(1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

Citation Fields

Format	Content	Examples
CDP (1)	Cited Patent	D 10 L3 CDP
CDP.B (1)	Cited Patent Basic	D CDP.B
CDPB (1)	Cited Patent Brief	D CDPB
CGP (1)	Citing Patent	D CGP 1-3
CGP.B (1)	Citing Patent Basic	D CGP.B
CGPB (1)	Citing Patent Brief	D CGPB
CRC	Cited References Count (Literature)	D CRC
CTCS	Citation Counters (all counters)	D CTCS
CTS	Citation Counters, Brief	D CTS
EXF	Examiner's Field of Search	D EXF
EXFB	Examiner's Field of Search Brief	D EXFB
REN	Reference (Literature)	D PA REN
REN.B	Reference (Literature) Basic	D REN.B
RENB	Reference (Literature) Brief	D RENB
UPG	Update Date Citing Patent	D UPG 13

(1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

DISPLAY and PRINT Formats (cont'd)

PREDEFINED FORMATS

Format	Content	Examples
ALL (MAX) (1) ALLB (STD) (1) DALL IALL (1) IALLB (ISTD) (1) ANL APPS (1) BIB (1) IBIB (1) BRIEF.D (1) BRIEF.G (1) CITN (1) CITNB (1) FAM (1) PATS (1) SCAN (2) TRIAL (TRI, SAM SAMPLE, FREE)	AN, TI, IN, PA, CYC, PI, ADT, FDT, PRAI, CTCS, EXF, CITN all data available but citations briefed up AN, TI, IN, PA, CYC, PI, ADT, FDT, PRAI, EXFB, CTS, CITNB (default) ALL, delimited for post-processing ALL, indented with text labels ALLB, indented with text labels Accession Number List (no answer numbers) ADT, PRAI AN, TI, IN, PA, CYC, PI, ADT, FDT, PRAI BIB, indented with text labels AN, TI, PA, CDP AN, TI, PA, CGP CDP, REN, CGP CDPB, RENB, CGPB PI, ADT, FDT, PRAI PI, FDT TI (abbreviated) (random display, no answer numbers) AN, TI (abbreviated)	D ALL 1-3 D ALLB D DALL D IALL D IALLB D ANL D APPS D BIB D IBIB D BRIEF.D D BRIEF.G D CITN D CITNB D FAM 1-10 D PATS 2-10 DISPLAY SCAN TRI 1-10
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

- (1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
(2) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Master Patent Fields

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Accession Number	AN	Y	N
Application Country	AC	Y	N
Application Date	AD	Y	N
Application Details	ADT	Y	N
Application Information	AI	Y	N
Application Number	AP (AI)	Y	N
Application Number Group	APPS	Y (2)	N
Application Number, Clarivate Analytics Format	APTS	Y	N
Application Year	AY	Y	N
Country Count	CYC	Y	Y
Designated State	DS	Y	N

SELECT, ANALYZE, and SORT Fields

Master Patent Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
WPI Week	DW	Y	Y
WPI Week Basic	DW.B	Y	Y
Entry Date	ED	Y	Y
Examiner's Field of Search Brief	EXFB	Y	N
Filing Details	FDT	Y	N
Inventor	IN (AU)	Y	Y
International Patent Classification of examiner's field of search	IC.F	Y	N
Language	LA	Y	N
National Classification of examiner's field of search	NCL.F	Y	N
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee Code and Name	PAX	Y	N
Patent Assignee Codes	PACO	Y	Y
Patent Countries	PCS	Y	N
Patent Country	PC	Y	N
Patent Country Basic	PC.B	Y	Y
PCI Week	PCIW	Y	Y
Patent Information	PI (PN)	Y	Y
Patent Information Basic	PI.B (PN.B)	Y	Y
Patent Kind Code	PK	Y	Y
Patent Kind Code Basic	PK.B	Y	Y
Patent Number Count	PNC	Y	Y
Patent Number Group	PATS	Y (3)	N
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date First	PRDF	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number, Clarivate Analytics	PRTS	Y	Y
Priority Year	PRY	Y	Y
Priority Year First	PRYF	Y (4)	Y
Publication Date	PD	Y	Y
Publication Date Basic	PD.B	Y	Y
Publication Year	PY	Y	Y
Publication Year Basic	PY.B	Y	Y
Title	TI	Y (default)	Y
Update Date	UP	Y	Y

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, by SELECT.
- (2) Selects or analyzes application and priority numbers with /APPS appended to the terms created by SELECT.
- (3) Selects or analyzes /FDT.PN and PN with /PATS appended to the terms created by SELECT.
- (4) SELECT or ANALYZE HIT are not valid with this field.

SELECT, ANALYZE, and SORT Fields (cont'd)

Citation Fields – Cited Patent

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Cited Accession Number Count	OSC.D	Y	Y
Cited Patent Assignee	PA.D	Y	N
Cited Patent Assignee (by examiner)	PA.DX	Y	N
Cited Patent Assignee (by inventor)	PA.DI	Y	N
Cited Patent Assignee Code	PACO.D	Y	N
Cited Patent Assignee Code (by examiner)	PACO.DX	Y	N
Cited Patent Assignee Code (by inventor)	PACO.DI	Y	N
Cited Patent Assignee Code (in opposition)	PACO.DO	Y	N
Cited Patent Assignee Code (by third party)	PACO.DTH	Y	N
Cited Patent Category (by examiner)	CAT.D	Y	N
Cited Patent Country	PC.D	Y	N
Cited Patent Country (by examiner)	PC.DX	Y	N
Cited Patent Country (by inventor)	PC.DI	Y	N
Cited Patent WPI Accession Number	OS.D	Y	N
Cited Patent WPI Accession Number (by examiner)	OS.DX	Y	N
Cited Patent WPI Accession Number (by inventor)	OS.DI	Y	N
Cited Patent Inventor	IN.D	Y	N
Cited Patent Inventor (by examiner)	IN.DX	Y	N
Cited Patent Inventor (by inventor)	IN.DI	Y	N
Cited Patent Kind Code	PK.D	Y	N
Cited Patent Kind Code (by examiner)	PK.DX	Y	N
Cited Patent Kind Code (by inventor)	PK.DI	Y	N
Cited Patent Number	PN.D	Y	N
Cited Patent Number (by examiner)	PN.DX	Y	N
Cited Patent Number (by inventor)	PN.DI	Y	N
Cited Patents Count	PNC.D	Y	Y
Cited Patents Count (by examiner)	PNC.DX	Y	Y
Cited Patents Count (by inventor)	PNC.DI	Y	Y
Cited Patents Count (in opposition)	PNC.DO	Y	Y
Cited Patents Count (by third party)	PNC.DTH	Y	Y
Cited Patents Count (undefined)	PNC.DUN	Y	Y
Issuing Authority Count Cited Patents	IAC.D	Y	Y
Issuing Authority Count Cited Patents (by examiner)	IAC.DX	Y	Y
Issuing Authority Count Cited Patents (by inventor)	IAC.DI	Y	Y
Patent Country of Family Member	PC.F	Y	N
Patent Kind Code of Family Member	PK.F	Y	N
Patent Number of Family Member	PN.F	Y	N

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, by SELECT.

Citation Fields – Cited Literature

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Cited Reference Count (by examiner)	CRC.X	Y	Y
Cited Reference Count (by inventor)	CRC.I	Y	Y
Cited Reference Count (in opposition)	CRC.O	Y	Y
Cited Reference Count (by third party)	CRC.TH	Y	Y
Cited Reference Count (undefined)	CRC.UN	Y	Y
Patent Country of Citing Family Member	REPC	Y	N
Patent Kind Code of Citing Family Member	REPK	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Citation Fields – Cited Literature (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Patent Number of Citing Family Number	REPN	Y	N
Reference (Literature) cited by examiner	REN.X	Y	N
Reference (Literature) cited by inventor	REN.I	Y	N
Reference Category	RENC	Y	N

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT T1.

Citation Fields – Citing Patents

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Citing Accession Number Count	OSC.G	Y	Y
Citing Patent Assignee	PA.G	Y	N
Citing Patent Assignee (by examiner)	PA.GX	Y	N
Citing Patent Assignee (by inventor)	PA.GI	Y	N
Citing Patent Assignee Code	PACO.G	Y	N
Citing Patent Assignee Code (by examiner)	PACO.GX	Y	N
Citing Patent Assignee Code (by inventor)	PACO.GI	Y	N
Citing Patent Assignee Code (in opposition)	PACO.GO	Y	N
Citing Patent Assignee Code (by third party)	PACO.GTH	Y	N
Citing Patent Category (cited by examiner)	CAT.G	Y	N
Citing Patent Country	PC.G	Y	N
Citing Patent Country (by examiner)	PC.GX	Y	N
Citing Patent Country (by inventor)	PC.GI	Y	N
Citing Patent Inventor	IN.G	Y	N
Citing Patent Inventor (by examiner)	IN.GX	Y	N
Citing Patent Inventor (by inventor)	IN.GI	Y	N
Citing Patent Kind Code	PK.G	Y	N
Citing Patent Kind Code (by examiner)	PK.GX	Y	N
Citing Patent Kind Code (by inventor)	PK.GI	Y	N
Citing Patent Number	PN.G	Y	N
Citing Patent Number (by examiner)	PN.GX	Y	N
Citing Patent Number (by inventor)	PN.GI	Y	N
Citing Patent WPI Accession Number	OS.G	Y	N
Citing Patent WPI Accession Number (by examiner)	OS.GX	Y	N
Citing Patent WPI Accession Number (by inventor)	OS.GI	Y	N
Citing Patents Number Count	PNC.G	Y	Y
Citing Patents Number Count (by examiner)	PNC.GX	Y	Y
Citing Patents Number Count (by inventor)	PNC.GI	Y	Y
Citing Patents Number Count (in opposition)	PNC.GO	Y	Y
Citing Patents Number Count (by third party)	PNC.GTH	Y	Y
Citing Patents Number Count (undefined)	PNC.GUN	Y	Y
Issuing Authority Count Citing Patents	IAC.G	Y	Y
Issuing Authority Count Citing Patents (by examiner)	IAC.GX	Y	Y
Issuing Authority Count Citing Patents (by inventor)	IAC.GI	Y	Y
Patent Country of Family Member	PC.F	Y	N
Patent Kind Code of Family Member	PK.F	Y	N
Patent Number of Family Member	PN.F	Y	N

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT T1.

Sample Records

DISPLAY ALL (STN FORMAT)

AN 2006-766865 [200678] DPCI
TI Collection method of opinions of push-to-talk-over cellular participants
in push-to-talk-over cellular network, involves determining whether voting
function is occupied by another user in group
IN JUNG B; JUNG B S; PARK J; PARK J G; PARK S; PARK S J; SUNG S; SUNG S K
PA (SMSU-C) SAMSUNG ELECTRONICS CO LTD
CYC 111
PI WO 2006101340 A1 20060928 (200678)* EN 27[11]
US 20060234745 A1 20061019 (200678) EN
KR 2006102054 A 20060927 (200705) KO
EP 1861959 A1 20071205 (200781) EN
CN 101147361 A 20080319 (200841) ZH
JP 2008537377 T 20080911 (200861) JA 20
US 7577454 B2 20090818 (200955) EN
ADT WO 2006101340 A1 WO 2006-KR1035 20060322; KR 2006102054 A KR 2005-23802
20050322; CN 101147361 A CN 2006-80009134 20060322; EP 1861959 A1 EP
2006-716484 20060322; US 20060234745 A1 US 2006-386491 20060322; US
7577454 B2 US 2006-386491 20060322; EP 1861959 A1 PCT Application WO
2006-KR1035 20060322; CN 101147361 A PCT Application WO 2006-KR1035
20060322; JP 2008537377 T PCT Application WO 2006-KR1035 20060322; JP
2008537377 T JP 2008-502904 20060322
FDT EP 1861959 A1 Based on WO 2006101340 A; CN 101147361 A Based on WO
2006101340 A; JP 2008537377 T Based on WO 2006101340 A
PRAI KR 2005-23802 20050322

CTCS CITATION COUNTERS

PNC.D 3 Cited Patents Count (total)
PNC.DI 0 Cited Patents Count (by inv.)
PNC.DX 3 Cited Patents Count (by exam.)
PNC.DO 0 Cited Patents Count (in opp. doc.)
PNC.DTH 0 Cited Patents Count (third party)
PNC.DUN 0 Cited Patents Count (undefined)
IAC.D 1 Cited Issuing Authority Count (total)
IAC.DI 0 Cited Issuing Authority Count (by inv.)
IAC.DX 1 Cited Issuing Authority Count (by exam.)
IAC.DO 0 Cited Issuing Authority Count (in opp. doc.)
IAC.DTH 0 Cited Issuing Authority Count (third party)
IAC.DUN 0 Cited Issuing Authority Count (undefined)

PNC.G 3 Citing Patents Count (total)
PNC.GI 0 Citing Patents Count (by inv.)
PNC.GX 3 Citing Patents Count (by exam.)
PNC.GO 0 Citing Patents Count (in opp. doc.)
PNC.GTH 0 Citing Patents Count (third party)
PNC.GUN 0 Citing Patents Count (undefined)
IAC.G 2 Citing Issuing Authority Count (total)
IAC.GI 0 Citing Issuing Authority Count (by inv.)
IAC.GX 2 Citing Issuing Authority Count (by exam.)
IAC.GO 0 Citing Issuing Authority Count (in opp. doc.)
IAC.GTH 0 Citing Issuing Authority Count (third party)
IAC.GUN 0 Citing Issuing Authority Count (undefined)

CRC 6 Cited Literature Reference Count (total)
CRC.I 0 Cited Literature Reference Count (by inv.)
CRC.X 6 Cited Literature Reference Count (by exam.)
CRC.O 0 Cited Literature Reference Count (in opp. doc.)

CRC.TH	0	Cited Literature Reference Count (third party)
CRC.UN	0	Cited Literature Reference Count (undefined)
OSC.D	3	Cited Patent WPI Accession Number Count (total)
OSC.DX	3	Cited Patent WPI Accession Number Count (by exam.)
OSC.DI	0	Cited Patent WPI Accession Number Count (by inv.)
OSC.DO	0	Cited Patent WPI Accession Number Count (in opp. doc.)
OSC.DTH	0	Cited Patent WPI Accession Number Count (third party)
OSC.DUN	0	Cited Patent WPI Accession Number Count (undefined)
OSC.G	2	Citing Patent WPI Accession Number Count (total)
OSC.GX	2	Citing Patent WPI Accession Number Count (by exam.)
OSC.GI	0	Citing Patent WPI Accession Number Count (by inv.)
OSC.GO	0	Citing Patent WPI Accession Number Count (in opp. doc.)
OSC.GTH	0	Citing Patent WPI Accession Number Count (third party)
OSC.GUN	0	Citing Patent WPI Accession Number Count (undefined)

CDP Cited Patents

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Citing Publication	By	Cat	Cited Patent	Date	Accession Number
WO 2006101340 A1	E	AP	US 20050105511 A1	20050519	2005-402691
			PA: (OYNO-C) NOKIA CORP		
			IN: POIKSELKA M		
	E	AP	US 20050215273 A1	20050929	2005-577964
			PA: (NIDE-C) NEC CORP		
			IN: ITO N; ITO NAKO		
US 7577454 B2	E		US 20020168992 A1	20021114	2003-077765
			PA: (OYNO-C) NOKIA CORP		
			IN: EIDEN N; LEHTO J		
	E		US 20050105511 A1	20050519	2005-402691
			PA: (OYNO-C) NOKIA CORP		
			IN: POIKSELKA M		
	E		US 20050215273 A1	20050929	2005-577964
			PA: (NIDE-C) NEC CORP		
			IN: ITO N; ITO NAKO		

REN Literature Citations

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Citing Publication	By	Cat	Literature Reference
WO 2006101340 A1	E	A	KIM P. ET AL.: 'IMS-based push-to-talk over GPRS/UMTS' WIRELESS COMMUNICATIONS AND NETWORKING CONFERENCE, 2005 IEEE vol. 4, 13 March 2005 - 17 March 2005, pages 2472 - 2477
	E	A	KIM P. ET AL.: 'IMS-based push-to-talk over GPRS/UMTS' WIRELESS COMMUNICATIONS AND NETWORKING CONFERENCE, 2005 IEEE vol. 4, 13 March 2005 - 17 March 2005, pages 2472 - 2477
	E	A	KIM P. ET AL.: 'IMS-based push-to-talk over GPRS/UMTS' WIRELESS COMMUNICATIONS AND NETWORKING CONFERENCE, 2005 IEEE vol. 4, 13 March 2005 - 17 March 2005, pages 2472 - 2477
	E	A	RAKTALE S.K.: '3PoC: an architecture for enabling push to talk services in 3GPP networks' PERSONAL WIRELESS COMMUNICATIONS, 2005. ICPWC 2005. 2005 IEEE INTERNATIONAL CONFERENCE 23 January 2005 - 25 January 2005, pages 202 - 206

	E	A	RAKTALE S.K.: '3PoC: an architecture for enabling push to talk services in 3GPP networks' PERSONAL WIRELESS COMMUNICATIONS, 2005. ICPWC 2005. 2005 IEEE INTERNATIONAL CONFERENCE 23 January 2005 - 25 January 2005, pages 202 - 206
	E	A	RAKTALE S.K.: '3PoC: an architecture for enabling push to talk services in 3GPP networks' PERSONAL WIRELESS COMMUNICATIONS, 2005. ICPWC 2005. 2005 IEEE INTERNATIONAL CONFERENCE 23 January 2005 - 25 January 2005, pages 202 - 206, XP010798546
US 7577454 B2	E		Kim et al., IMS-Based Push-to-Talk Over GPRS/UMTS, Wireless Communications and Networking Conference, Mar. 13-17, 2005; pp. 2472-2477.
	E		Raktale, 3PoC: An Architecture for Enabling Push to Talk Services in 3GPP Networks, 2005 IEEE International Conference on Personal Wireless Communications, Jan. 23-25, 2005, pp. 202-206.

CGP Citing Patents

Cited Publication	By	Cat	Citing Patent	Date	Accession Number
WO 2006101340 A1	E		GB 2429614 A	20070228	2007-047063
			PA: (INFN-C) INFINEON TECHNOLOGIES AG		
			IN: SCHMIDT A; SCHMIDT H; SCHWAGMANN N		
	E		GB 2429614 B	20071205	2007-047063
			PA: (INFN-C) INFINEON TECHNOLOGIES AG		
			IN: SCHMIDT A; SCHMIDT H; SCHWAGMANN N		
US 7577454 B2	E		US 7797011 B2	20100914	2006-343816
			PA: (MATU-C) MATSUSHITA ELECTRIC IND CO LTD		
			IN: SAITO J		

DISPLAY ALLB (Derwent Format)

AN 2006-512665 [200652] DPCI

TI New crystalline polymorph of a monohydrate is CXC-chemokine receptor modulator, useful to treat e.g. hepatitis viruses, HIV, hypercapnea, hyperinflation, hypoxemia, transplant reperfusion injury and autoimmune deafness

IN AGNES K; DWYER M; FU X; HU M; KIM M A; KIMMEADE A; KIM-MEADE A; KLOPPER K; KLOPPER K; MCALLISTER T; TAVARAS A G; TAVERAS A; TAVERAS A G; YIN J; YU Y; ZHANG S

PA (SCHE-C) SCHERING CORP

CYC 108

PI WO--2005075447 A1 20050818 (200652)* EN 65[3]

US-20050192345 A1 20050901 (200652) EN

EP-----1723131 A1 20061122 (200677) EN

NO---200603841 A 20061027 (200677) NO

AU--2005210504 A1 20050818 (200707) EN

MX--2006008599 A1 20060901 (200707) ES

KR--2006128981 A 20061214 (200742) KO

BR---200507329 A 20070703 (200746) PT

CN-----1914187 A 20070214 (200746) ZH

IN---200602800 P4 20070608 (200748) EN

JP--2007519751 W 20070719 (200749) JA 49
ZA---200606295 A 20080227 (200821) EN 81
US-20080279822 A1 20081113 (200877) EN
KR-----883476 B1 20090216 (200924) KO
AU--2005210504 B2 20090108 (200951) EN
TW---200536848 A 20051116 (200978) ZH
IN-----234129 B 20090529 (200981) EN
MX-----270930 B 20091015 (201009) ES
RU-----2388756 C2 20100510 (201034) RU
NZ-----548499 A 20100625 (201052) EN
EP-----1723131 B1 20100818 (201054) EN
DE602005022986 E 20100930 (201064) DE
ADT WO--2005075447 A1 2005WO-US0003414 20050128; US-20050192345 A1 Provisional
2004US-000540487P 20040130; US-20080279822 A1 Provisional
2004US-000540487P 20040130; AU--2005210504 A1 2005AU-000210504 20050128;
AU--2005210504 B2 2005AU-000210504 20050128; BR---200507329 A
2005BR-000007329 20050128; CN-----1914187 A 2005CN-080003507 20050128;
DE602005022986 E DE 2005-602005022986 20050128; EP-----1723131 A1
2005EP-000712748 20050128; EP-----1723131 B1 2005EP-000712748 20050128;
DE602005022986 E 2005EP-000712748 20050128; NZ-----548499 A
2005NZ-000548499 20050128; TW---200536848 A 2005TW-000102703 20050128;
US-20050192345 A1 2005US-000045772 20050128; US-20080279822 A1 Cont of
2005US-000045772 20050128; EP-----1723131 A1 PCT Application
2005WO-US0003414 20050128; NO---200603841 A PCT Application
2005WO-US0003414 20050128; MX--2006008599 A1 PCT Application
2005WO-US0003414 20050128; KR--2006128981 A PCT Application
2005WO-US0003414 20050128; BR---200507329 A PCT Application
2005WO-US0003414 20050128; IN---200602800 P4 PCT Application
2005WO-US0003414 20050128; JP--2007519751 W PCT Application
2005WO-US0003414 20050128; KR-----883476 B1 PCT Application
2005WO-US0003414 20050128; IN-----234129 B PCT Application
2005WO-US0003414 20050128; MX-----270930 B PCT Application
2005WO-US0003414 20050128; RU-----2388756 C2 PCT Application
2005WO-US0003414 20050128; NZ-----548499 A PCT Application
2005WO-US0003414 20050128; EP-----1723131 B1 PCT Application
2005WO-US0003414 20050128; DE602005022986 E PCT Application
2005WO-US0003414 20050128; JP--2007519751 W 2006JP-000551613 20050128;
RU-----2388756 C2 2006RU-000131050 20050128; IN---200602800 P4
2006IN-CHENP02800 20060728; IN-----234129 B 2006IN-CN0002800 20060728;
KR--2006128981 A 2006KR-000715429 20060728; KR-----883476 B1
2006KR-000715429 20060728; MX--2006008599 A1 2006MX-000008599 20060728;
MX-----270930 B 2006MX-000008599 20060728; ZA---200606295 A
2006ZA-000006295 20060728; NO---200603841 A 2006NO-000003841 20060829;
US-20080279822 A1 2008US-000174470 20080716
FDT DE602005022986 E Based on EP-----1723131 A; KR-----883476 B1 Previous
Publ KR--2006128981 A; EP-----1723131 A1 Based on WO--2005075447 A;
AU--2005210504 A1 Based on WO--2005075447 A; MX--2006008599 A1 Based on
WO--2005075447 A; KR--2006128981 A Based on WO--2005075447 A;
BR---200507329 A Based on WO--2005075447 A; JP--2007519751 W Based on
WO--2005075447 A; KR-----883476 B1 Based on WO--2005075447 A;
AU--2005210504 B2 Based on WO--2005075447 A; MX-----270930 B Based on
WO--2005075447 A; RU-----2388756 C2 Based on WO--2005075447 A;
NZ-----548499 A Based on WO--2005075447 A; EP-----1723131 B1 Based on
WO--2005075447 A; DE602005022986 E Based on WO--2005075447 A
PRAI 2004US-000540487P 20040130
2008US-000174470 20080716
2005US-000045772 20050128
2004US-000540487 20040130

CTS CITATION COUNTERS

PNC.D 5 Cited Patents Count
PNC.G 7 Citing Patents Count
IAC.D 3 Cited Issuing Authority Count
IAC.G 3 Citing Issuing Authority Count
CRC 4 Cited Literature Reference Count
OSC.D 4 Cited Patent WPI Accession Number Count
OSC.G 7 Citing Patent WPI Accession Number Count

Citations

Cited Publication By Accession Number

AU--2002311841 B2 E 2003-092974
RU-----2190607 C2 E 1996-068807
RU-----2220721 C2 E 1999-359839
WO--2002083624 A1 E 2003-092974
WO--2003080053 A1 E 2003-833503

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By Literature Reference

E Cairn, Topics in Current Chemistry, Springer, Berlin, DE, 1998, vol. 198 pages 163-208
E CAIRA M R: "CRYSTALLINE POLYMORPHISM OF ORGANIC COMPOUNDS" TOPICS IN CURRENT CHEMISTRY, SPRINGER, BERLIN, DE, vol. 198, 1998, pages 163-208, XP001156954 ISSN: 0340-1022
E CAIRA M R: "CRYSTALLINE POLYMORPHISM OF ORGANIC COMPOUNDS" TOPICS IN CURRENT CHEMISTRY, SPRINGER, BERLIN, DE, vol. 198, 1998, pages 163-208, XP001156954 ISSN: 0340-1022
E See references of WO 2005075447A1

Citings

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